4D particle tracking with Resistive AC-Coupled Silicon Detectors (RSD)

Marco Mandurrino

marco.mandurrino@to.infn.it

From LGAD to RSD

- To get rid of the dead area between pixels, as in standard LGADs, we implemented a new readout paradigm: the Resistive AC-Coupled Silicon Detector technology
- In RSD the readout is analogic, and no more binary, with bipolar signals
- RSD benefit from the good timing performances proper of LGADs, but with an increased capability to track particles in space: they are suitable for 4D tracking
- ► 100% fill-factor and analogic readout make possible to reconstruct the hit position with a precision ~2 orders of magnitude lower than the pad pitch





Development timeline

- The Resistive AC-Coupled Silicon Detector technology was first proposed for a proof of princicle in the CSN5 grant called RSD (PI: M. Mandurrino), in strong synergy with the UFSD project in Torino
- ► First production submitted Jan 2019
- Promising results and indication from RSD1
- ► Moreover, all the main signal properties are conserved in large-area RSD detectors
- ► Second production submitted end of 2020
- ► What is missing? electrical tests at FBK, not yet arrived in Torino
- Why perfect for Muon Collider?

The first production: RSD1

Production layout and technological splits

wafer #	<i>n</i> -plus dose	<i>p</i> -gain dose	diel. thickness	substrate
1	В	0.92	Low	FZ
2	В	0.94	Low	FZ
3	В	0.94	Low	Ері
4	В	0.94	High	FZ
5	В	0.96	High	FZ
6	С	0.92	Low	Ері
7	С	0.94	Low	FZ
8	С	0.94	Low	FZ
9	С	0.96	Low	FZ
10	С	0.96	High	FZ
11	D	0.92	Low	FZ
12	D	0.94	Low	Ері
13	D	0.94	Low	FZ
14	D	0.96	High	Ері
15	D	0.96	High	FZ

Split table of parameters implemented in RSD1 (2019)





RSD and 4D-tracking – RSD1



Correlation between hit position and signal amplitude/delay

Laser measurements

The space/time resolution increase at high gain and small pad pitch/size

RSD1	Gain 12		Gain 17		Gain 24	
	$\sigma_x \; [\mu \mathrm{m}]$	σ_t [ps]	$\sigma_x \; [\mu { m m}]$	σ_t [ps]	$\sigma_x \; [\mu { m m}]$	$\sigma_t [\mathrm{ps}]$
100/70	3.2	17.6	2.8	15.3	2.5	13.9
200/100	8.6	31.1	6.2	22.3	-	-
200/190	17.9	58.7	14.3	62.6	8.8	59.9
500/200	27.3	45.7	20.6	34.6	20.6	32.6

FNAL testbeam (RSD 200/100)

 $\sigma_x = \sim 5 \,\mu \text{m}$ and $\sigma_t = \sim 40 \,\text{ps}$

4D-tracking with RSD

Hit reconstruction



ML algorithms



Production layout and technological splits

wafer #	<i>n</i> -plus dose	<i>p</i> -gain dose	met. thickness	substrate	С
1	А	0.96	thick	FZ	Ν
2	А	0.96	normal	FZ	Ν
3	А	0.98	normal	FZ	Ν
4	А	1.00	normal	FZ	Ν
5	В	1.00	normal	FZ	Ν
6	В	1.00	normal	Ері	Ν
7	В	0.98	normal	FZ	Ν
8	В	0.96	normal	Ері	Ν
9	В	0.96	normal	Ері	Ν
10	В	0.96	normal	Ері	Y
11	С	0.96	normal	Ері	Ν
12	С	0.96	normal	Ері	Y
13	С	0.98	normal	FZ	Ν
14	С	0.98	normal	Ері	Ν
15	С	0.94	normal	FZ	Ν

Split table of parameters implemented in RSD2 (2021)



Low dielectric thickness Epi: 45 μm / FZ: 55 μm

M. Mandurrino INFN Torino

Sensors layout



Testing campaigns

► RSD1:

measurements on irradiated structures

► RSD2:

- ► I(V) and C(V)
- ► gain measurements
- ► resistivity
- signal properties
- irradiation campaigns
- ► test-beams

RSD for RD_MUCOL

Present RSD are designed and produced for different general purpose particle-physics experiments (thick substrates, medium granularity, very low gain)

RSD optimized for a muon collider need for:

- Iow material budget (thin handle wafers)
- ► the **optimal geometry** to comply with the physics requirements
- ► production of **large-area** detectors
- ► radiation-hardness studies

Costs for one RSD production at FBK:

► batch of 25 6-inches epitaxial wafers and production under the INFN-FBK collaboration framework: 30 kEuro

Selected references on RSD

- ► LGAD design: <u>https://doi.org/10.1201/9781003131946</u> (Chapter 3)
- ► RSD design: <u>http://dx.doi.org/10.1016/j.nima.2020.163479</u>
- ► First RSD1 tests: <u>http://dx.doi.org/10.1109/LED.2019.2943242</u>
- ► FNAL testbeam: <u>https://arxiv.org/abs/2007.09528</u>

Thank you!

Backup

M. Mandurrino INFN Torino

4D-tracking with RSD

The first production: RSD1

Detector testing

Electrical characterization campaigns on RSD1 have shown that FBK is able to reproduce the **optimal physical-technological parameters** we found at INFN through **numerical modeling** with high precision, reproducibility and homogeneity.

We also demonstrated to reach the challenging goal of producing (working) 100% fill-factor Silicon detectors with internal gain and high-segmentation level:



(Preliminary) electrical tests at FBK



wafer #	<i>n</i> -plus dose	<i>p</i> -gain dose	met. thickness	substrate	с
1	А	0.96	thick	FZ	Ν
2	А	0.96	normal	FZ	Ν
3	А	0.98	normal	FZ	Ν
4	А	1.00	normal	FZ	Ν
5	В	1.00	normal	FZ	Ν
6	В	1.00	normal	Ері	Ν
7	В	0.98	normal	FZ	Ν
8	В	0.96	normal	Ері	Ν
9	В	0.96	normal	Ері	Ν
10	В	0.96	normal	Ері	Y
11	С	0.96	normal	Ері	Ν
12	С	0.96	normal	Ері	Y
13	С	0.98	normal	FZ	Ν
14	С	0.98	normal	Ері	N
15	С	0.94	normal	FZ	N

(Preliminary) electrical tests at FBK



wafer #	<i>n</i> -plus dose	<i>p</i> -gain dose	met. thickness	substrate	С
1	А	0.96	thick	FZ	Ν
2	А	0.96	normal	FZ	Ν
3	А	0.98	normal	FZ	Ν
4	А	1.00	normal	FZ	Ν
5	В	1.00	normal	FZ	Ν
6	В	1.00	normal	Ері	Ν
7	В	0.98	normal	FZ	Ν
8	В	0.96	normal	Ері	Ν
9	В	0.96	normal	Ері	Ν
10	В	0.96	normal	Ері	Y
11	С	0.96	normal	Epi	Ν
12	С	0.96	normal	Ері	Y
13	С	0.98	normal	FZ	Ν
14	С	0.98	normal	Ері	Ν
15	С	0.94	normal	FZ	Ν

(Preliminary) electrical tests at FBK



wafer #	<i>n</i> -plus dose	<i>p</i> -gain dose	met. thickness	substrate	с
1	А	0.96	thick	FZ	Ν
2	А	0.96	normal	FZ	Ν
3	А	0.98	normal	FZ	Ν
4	А	1.00	normal	FZ	Ν
5	В	1.00	normal	FZ	Ν
6	В	1.00	normal	Ері	Ν
7	В	0.98	normal	FZ	Ν
8	В	0.96	normal	Ері	Ν
9	В	0.96	normal	Ері	Ν
10	В	0.96	normal	Ері	Y
11	С	0.96	normal	Ері	Ν
12	С	0.96	normal	Epi	Y
13	С	0.98	normal	FZ	N
14	С	0.98	normal	Ері	N
15	С	0.94	normal	FZ	Ν